2SD1249, 2SD1249A

Silicon NPN triple diffusion planar type

For low-freauency power amplification

■ Features

- ullet High collector-base voltage (Emitter open) V_{CBO}
- N type package enabling direct soldering of the radiating fin to the printed circuit board, etc. of small electronic equipment.

■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SD1249	V _{CBO}	350	V
(Emitter open)	2SD1249A		400	
Collector-emitter voltage	2SD1249	V _{CEO}	250	V
(Base open)	2SD1249A		300	
Emitter-base voltage (Col	V_{EBO}	5	V	
Collector current	I_{C}	0.75	A	
Peak collector current	I_{CP}	1.5	A	
Collector power dissipation	P _C	35	W	
	$T_a = 25^{\circ}C$	A. (1.3	
Junction temperature	Tj	150	°C	
Storage temperature	A	T_{stg}	-55 to +150	°C

Unit: mm 8.5±0.2 6.0±0.2 1.0±0.1 1.

Note) Self-supported type package is also prepared.

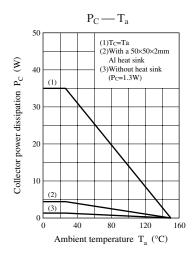
■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

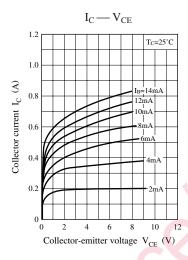
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SD1249	V _{CEO}	$I_{\rm C} = 30 \text{ mA}, I_{\rm B} = 0$	250			V
(Base open)	2SD1249A		Sqille Co to.	300			
Collector-emitter cutoff	2SD1249	I _{CES}	$V_{CE} = 350 \text{ V}, V_{BE} = 0$			1	mA
current (E-B short)	2SD1249A		$V_{CE} = 400 \text{ V}, V_{BE} = 0$			1	
Collector-emitter cutoff	2SD1249	I _{CEO}	$V_{CE} = 150 \text{ V}, I_{B} = 0$			1	mA
current (Base open)	2SD1249A	SUC.	$V_{CE} = 200 \text{ V}, I_{B} = 0$			1	
Emitter-base cutoff current (Collector open)		I_{EBO}	$V_{EB} = 5 \text{ V}, I_{C} = 0$			1	mA
Forward current transfer ratio		h _{FE1} *	$V_{CE} = 10 \text{ V}, I_{C} = 0.3 \text{ A}$	40		250	_
		h _{FE2}	$V_{CE} = 10 \text{ V}, I_{C} = 1 \text{ A}$	10			
Base-emitter voltage		V_{BE}	$V_{CE} = 10 \text{ V}, I_{C} = 1 \text{ A}$			1.5	V
Collector-emitter saturation voltage		V _{CE(sat)}	$I_C = 1 A, I_B = 0.2 A$			1.0	V
Transition frequency		f_T	$V_{CE} = 10 \text{ V}, I_{C} = 0.2 \text{ A}, f = 10 \text{ MHz}$		30		MHz
Turn-on time		t _{on}	I _C = 1 A		0.5		μs
Strage time		t _{stg}	$I_{B1} = 0.1 \text{ A}, I_{B2} = -0.1 \text{ A}$		2.0		μs
Fall time		t_{f}	$V_{CC} = 50 \text{ V}$		0.5		μs

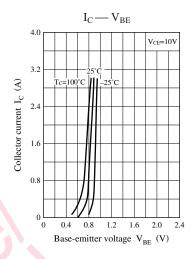
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

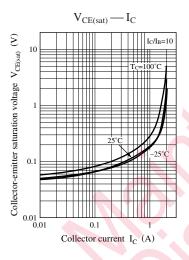
2. *: Rank classification

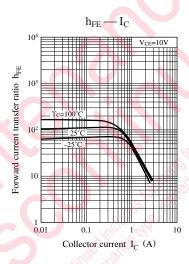
Rank	R	Q	Р
$h_{\rm FE1}$	40 to 90	70 to 150	120 to 250

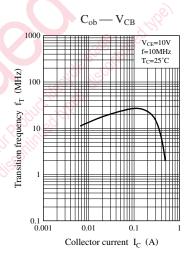


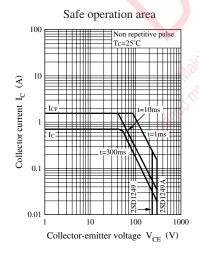


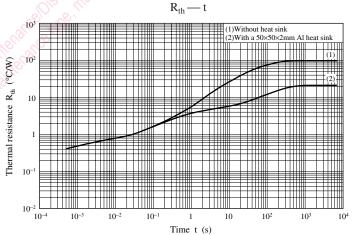












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